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DISCLOSURE STATEMENT TRANSMITTAL To Commissioner For Patents Enclosed herewith is a Form PTO-1449, any required copies of			Filing Date			"/					
			First Named Inventor	PINEDA DE GYVEZ, Jose							
			Group Art Unit 281.6 Examiner Name Diph Le								
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documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.				Atty. Docket Number	NL02 1186 US						
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^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

^{**}Unique citation designation number. ** See attached Kinds of U.S. Patent Documents. ** Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). *For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ** Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 18 if possible. **Applicant is to place a check mark here if English language Translation is attached.